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Term:	L16 and cookie
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DATE: Friday, April 16, 2004 [Printable Copy](#) [Create Case](#)

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<u>L17</u>	L16 and cookie	1	<u>L17</u>
<u>L16</u>	('5774670')!.PN.	1	<u>L16</u>
<u>L15</u>	('6134592' '5774670')!.PN.	2	<u>L15</u>
<u>L14</u>	L13 and (delet\$3 near6 cookie)	3	<u>L14</u>
<u>L13</u>	('6510464' '6480853' '6401125' '6353849' '6134592' '5826242' '5774670')!.PN.	7	<u>L13</u>
<u>L12</u>	L11 and @ad<20010101	25	<u>L12</u>
<u>L11</u>	server near6 (list or profile) near6 cookie	68	<u>L11</u>
<u>L10</u>	L8 and @ad<20010101	6	<u>L10</u>
<u>L9</u>	L8 and @ad<2001001	0	<u>L9</u>
<u>L8</u>	(server near3 list near3 cookie)	17	<u>L8</u>
<u>L7</u>	L6 and (server near3 list near3 cookie)	1	<u>L7</u>
<u>L6</u>	('20030041263' '20020007317' '6678731')!.PN.	3	<u>L6</u>
<u>L5</u>	L4 and cookie	5	<u>L5</u>
<u>L4</u>	('20030041263' '20020007317' '6678731' '6584505' '6134592')!.PN.	5	<u>L4</u>

L3 L2 and @ad<20010101

L2 L1 and (delet\$3 near3 cookie)

L1 list near3 cookie

13 L3

24 L2

118 L1

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1 [Ethics and electronic commerce](#)

Shona Leitch, Matthew Warren

 November 2000 **Selected papers from the second Australian Institute conference on Computer ethics - Volume 1**

 Full text available: pdf(415.15 KB) [Additional Information: full citation, abstract, references](#)

Ethics is an important element in all aspects of computing, but proves to be a real problem in the development and delivery of electronic commerce systems. There are many aspects of ethics that can affect electronic commerce systems, but perhaps the most notable and worrying to both consumers and developers is that of trust. In a world where so much information is transmitted and shared electronically, ethical standards that in general society are applied to this medium, are often ignored or forg ...

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